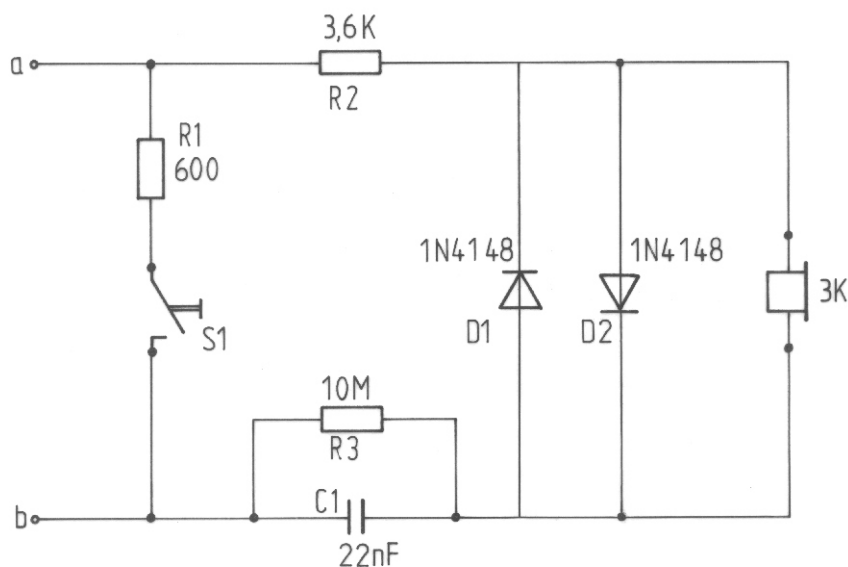


Operating Instructions

Test device no. 1a (test headphone)

The test device no. 1a is used in local and long distance automatic exchange for testing, error limiting and tracking of signals on the line.

According to the illustrated switching, the impedance of the device can be changed over. It has a value of 600 Ohm with closed switch S for d.c. and a.c. with opened switch, the resistance for d.c. is approx. 10 Mohm and in the frequency range of 300-4000 Hz > 10 kOhm, this means that when switching the device onto a line, which is on both sides closed with 600 Ohm, the insertion loss is < 0.26 dB. In this case the device has a receiving reference equivalent of < + 4.34 dB.



All components are placed on a printed circuit board. Further, two screw clamps a-b or soldering eyelets F-F for connection of the cord or of the hearing system are also on this board. A rotatable knurled disc at the back of the device activates the switch S. This has a recess designed as a window, in which appears, according to the switch position, a red field marked with 600 Ohm, or a green field marked with 10 kOhm.

The use of the test device (Prg 1a) is only authorised for telecommunication engineering devices according to DIN VDE 0800, part 1.

The device tolerates a permanent load of max. 2 Watt. This value is not nearly reached with switch position "10 kOhm" in the entire application area of the test device. If the device is to be connected in switch position "600 Ohm" for an unlimited period to a voltage of < 60 V, then the current must not be greater than 57 mA (at 60 V:40 Ohm, connect a resistance of 1.5 Watt on line side, with < 34 V no resistance is necessary). If a current of > than 57 mA is to be expected, then switch on is only admissible with a series resistor.

The switch position "10 kOhm" (green) serves the potential test (click testing) in high and low Ohm direct current circuits as well as the line tracking through listening into a sound signal; the switch position "600 Ohm" (red) is used during function tests in relay current circuits.